

Regional News

1317 Madison Wisconsin Section



**Hosted By: Promega Corporation
June 10, 2009**

Twenty two people were in attendance at the Madison Section meeting held at Promega Corporation in Madison, Wisconsin. Bucherview Metrology Services sponsored the meeting by renting the facility and providing morning snacks.

The meeting got started by our host and the Madison Section coordinator, Jay Bucher, who welcomed everyone, and opened the meeting by having all the attendees give their name, company and what they do. After the introductions, the program got underway. Our first presenter was James Jenkins from Quametec. His presentation on "QIM-Tonline.com: New Services, Tools and Community Centre" was very informative. Most had never been to his website and found the numerous tools and applications very interesting.

After a short break, our next presenter, Phil Smith from A2LA, gave a presentation on "Most Common Deficiencies Found during an ISO/IEC 17025 Assessment." The information on the various deficiencies along with Phil's unique perspective as an assessor gave the attendees an inside look at what some companies are doing wrong, and in some cases, what they are doing right. While the vast majority of attendees come from a non-calibration laboratory environment (they do not fall under ISO/IEC 17025 requirements), not complying with written standards is a universal discrepancy in all environments.

After Phil's presentation, door prizes were drawn and the group picture was taken. We would like to thank Bucherview Metrology Services, A2LA, Mike Boothe, JH Metrology Company Inc., Dytec/Midwest, and Promega Corporation for providing door prizes. Everyone received something, with an MP3 player being drawn as the grand prize.

After lunch, Phil Smith gave another presentation entitled "How to Specify Accredited Services" This was especially informative for most attendees as they either send out their standards, or all of their equipment to various vendors for traceable calibration. The information and background materials for why and how this might be accomplished was well received by those in attendance.

Then Jay Bucher, Bucherview Metrology Services, gave his presentation entitled "Paperless Records – Meeting 21 CFR Part 11." Although most were not paperless at the time, the presentation and discussion demonstrated that with little time and money they could easily be paperless within their organizations, while meeting the requirements the FDA has for using electronic records and electronic signatures.

We would like to thank Phil Smith and James Jenkins for giving freely of their time and knowledge to help make this section meeting a success. Of course, without the active participation of the attendees it would all be for naught. Thanks to them for attending and keeping the conversations and discussions lively and informative. Our next section meeting will be in the fall, and we hope to see everyone again at that time.

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